INDEX

Journal of Quality Technology

Volume 23, Nos. 1–4, 1991

ARTICLES

All articles, including material that appears in the Computer Programs and Technical Aids Departments, are listed alphabetically by author and numbered sequentially. These numbers are used to identify the articles in the Key Words list, Which begins on page 379.

1. ALLOWAY, J. A., JR. AND RAGHAVACHARI, M., *Control Chart Based on the Hodges-Lehmann Estimator* October, 336–347
2. BAIN, L. J. AND ENGELHARDT, M., *Reliability Test Plans for One-Shot Devices Based on Repeated Samples* ..... October, 304–311
3. BAIN, P. T. AND PATEL, J. K., *Factors for Calculating Prediction Intervals for Samples from a One-Parameter Exponential Distribution* ..... January, 48–52

BEMENT, T. R., see EASTERLING, R. G. ..... January, 1–11

4. BERK, K. N. AND PICARD, R. R., *Significance Tests for Saturated Orthogonal Arrays* ..... April, 79–89
5. BLACKWOOD, L. G., AND BRADLEY, E. L., *An Omnibus Test for Comparing Two Measuring Devices* January, 12–16
6. BOUCHER, T. O. AND JAFARI, M. A., *The Optimum Target Value for Single Filling Operations with Quality Sampling Plans* ..... January, 44–47
7. BOURKE, P. D., *Detecting a Shift in Fraction Nonconforming Using Run Length Control Charts with 100% Inspection* ..... July, 225–238
8. BOYLES, R. A., *The Taguchi Capability Index* ..... January, 17–26

BRADLEY, E. L., see BLACKWOOD, L. G. ..... January, 12–16

9. CHAKRABORTI, S. AND GIBBONS, J. D., *One-Sided Nonparametric Comparison of Treatments with a Standard in the One-Way Layout* ..... April, 102–106

CHOU, Y.-M., see FOUNTAIN, R. L. ..... April, 90–95

CLEMENT, J., see WALKER, E. ..... July, 247–252

10. CROSIER, R. B., *FORTRAN Programming Techniques* ..... October, 348–354

DAVIS, R. B., see JIN, C. ..... October, 355–358

11. DEUTLER, T., *Grubbs-Type Estimators for Reproducibility Variances in an Interlaboratory Test Study* October, 324–335
12. EASTERLING, R. G.; JOHNSON, M. E.; BEMENT, T. R.; AND NACHTSHEIM, C. J., *Statistical Tolerancing Based on Consumer's Risk Considerations* ..... January, 1–11

ENGELHARDT, M., see BAIN, L. J. ..... October, 304–311

13. FALTIN, F. W. AND WOODALL, W. H., *Discussion* ..... July, 194–197

FILLIBEN, J. J., see KACKER, R. N. ..... April, 107–116

14. FOUNTAIN, R. L. AND CHOU, Y.-M., *Minimum Sample Sizes for Two-Sided Tolerance Intervals for Finite Populations* ..... April, 90–95
15. GAN, F. F., *An Optimal Design of CUSUM Quality Control Charts* ..... October, 279–286
16. GAN, F. F., *Computing the Percentage Points of the Run Length Distribution of an Exponentially Weighted Moving Average Control Chart* ..... October, 359–365

GIBBONS, J. D., see CHAKRABORTI, S. ..... April, 102–106

17. GRIZE, Y. L., *Plotting Scaled Effects from Unreplicated Orthogonal Experiments* ..... July, 205–212
18. HACKL, P. AND LEDOLTER, J., *A Control Chart Based on Ranks* ..... April, 117–124

JAFARI, M. A., see BOUCHER, T. O. ..... January, 44–47

19. JARAIEDI, M. AND ZHUANG ZIQUING, *Determination of Optimal Design Parameters of $\bar{X}$ Charts When there is a Multiplicity of Assignable Causes* ..... July, 253–258
20. JIN, C. AND DAVIS, R. B., *Calculation of Average Run Lengths for Zone Control Charts with Specified Zone Scores* ..... October, 355–358

JOHNSON, M. E., see EASTERLING, R. G. ..... January, 1–11

INDEX

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3. BAIN, P. T. AND PATEL, J. K., *Factors for Calculating Prediction Intervals for Samples from a One-Parameter Exponential Distribution* ..... January, 48–52

BEMENT, T. R., see EASTERLING, R. G. ..... January, 1–11

4. BERK, K. N. AND PICARD, R. R., *Significance Tests for Saturated Orthogonal Arrays* ..... April, 79–89
5. BLACKWOOD, L. G., AND BRADLEY, E. L., *An Omnibus Test for Comparing Two Measuring Devices* January, 12–16
6. BOUCHER, T. O. AND JAFARI, M. A., *The Optimum Target Value for Single Filling Operations with Quality Sampling Plans* ..... January, 44–47
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8. BOYLES, R. A., *The Taguchi Capability Index* ..... January, 17–26

BRADLEY, E. L., see BLACKWOOD, L. G. ..... January, 12–16

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CHOU, Y.-M., see FOUNTAIN, R. L. ..... April, 90–95

CLEMENT, J., see WALKER, E. ..... July, 247–252

10. CROSIER, R. B., *FORTRAN Programming Techniques* ..... October, 348–354

DAVIS, R. B., see JIN, C. ..... October, 355–358

11. DEUTLER, T., *Grubbs-Type Estimators for Reproducibility Variances in an Interlaboratory Test Study* October, 324–335
12. EASTERLING, R. G.; JOHNSON, M. E.; BEMENT, T. R.; AND NACHTSHEIM, C. J., *Statistical Tolerancing Based on Consumer's Risk Considerations* ..... January, 1–11

ENGELHARDT, M., see BAIN, L. J. ..... October, 304–311

13. FALTIN, F. W. AND WOODALL, W. H., *Discussion* ..... July, 194–197

FILLIBEN, J. J., see KACKER, R. N. ..... April, 107–116

14. FOUNTAIN, R. L. AND CHOU, Y.-M., *Minimum Sample Sizes for Two-Sided Tolerance Intervals for Finite Populations* ..... April, 90–95
15. GAN, F. F., *An Optimal Design of CUSUM Quality Control Charts* ..... October, 279–286
16. GAN, F. F., *Computing the Percentage Points of the Run Length Distribution of an Exponentially Weighted Moving Average Control Chart* ..... October, 359–365

GIBBONS, J. D., see CHAKRABORTI, S. ..... April, 102–106

17. GRIZE, Y. L., *Plotting Scaled Effects from Unreplicated Orthogonal Experiments* ..... July, 205–212
18. HACKL, P. AND LEDOLTER, J., *A Control Chart Based on Ranks* ..... April, 117–124

JAFARI, M. A., see BOUCHER, T. O. ..... January, 44–47

19. JARAIEDI, M. AND ZHUANG ZIQUING, *Determination of Optimal Design Parameters of $\bar{X}$ Charts When there is a Multiplicity of Assignable Causes* ..... July, 253–258
20. JIN, C. AND DAVIS, R. B., *Calculation of Average Run Lengths for Zone Control Charts with Specified Zone Scores* ..... October, 355–358

JOHNSON, M. E., see EASTERLING, R. G. ..... January, 1–11

21. KACKER, R. N.; LAGERGREN, E. S.; AND FILLIBEN, J. J., *Taguchi's Fixed-Element Arrays are Fractional Factorials* ..... April, 107–116
22. KENETT, R. S., *Two Methods for Comparing Pareto Charts* ..... January, 27–31
23. KOONS, G. F. AND LUNER, J. J., *SPC in Low-Volume Manufacturing: A Case Study* ..... October, 287–295
LAGERGREN, E. S., see KACKER, R. N. ..... April, 107–116
LEDOLTER, J., see HACKL, P. ..... April, 117–124
LUNER, J. J., see KOONS, G. F. ..... October, 287–295
24. MACGREGOR, J. F., *Discussion* ..... July, 198–199
MASTRANGELO, C. M., see MONTGOMERY, D. C. ..... July, 203–204
MASTRANGELO, C. M., see MONTGOMERY, D. C. ..... July, 179–193
25. MELLOY, B. J., *Determining the Optimal Process Mean and Screening Limits for Packages Subject to Compliance Testing* ..... October, 318–323
26. MONTGOMERY, D. C. AND MASTRANGELO, C. M., *Response* ..... July, 203–204
27. MONTGOMERY, D. C. AND MASTRANGELO, C. M., *Some Statistical Process Control Methods for Autocorrelated Data* ..... July, 179–193
NACHTSHEIM, C. J., see EASTERLING, R. G. ..... January, 1–11
28. NELSON, L. S., *Additional Critical Values for Multiple Comparisons by Cluster Analysis* ..... October, 366–368
29. NELSON, L. S., *Polynomial Interpolation* ..... July, 259–262
30. NELSON, L. S., *Power in Comparing Poisson Means: I. One-Sample Test* ..... January, 68–70
31. NELSON, L. S., *Power in Comparing Poisson Means: II. Two-Sample Test* ..... April, 163–166
PATEL, J. K., see BAIN, P. T. ..... January, 48–52
32. PATEL, J. K. AND SAMARANAYAKE, V. A., *Prediction Intervals for Some Discrete Distributions* .. October, 270–286
PETERS, M. H., see VAUGHAN, T. S. ..... January, 32–43
PFEIFER, P. E., see SCHMIDT, R. L. ..... October, 312–317
PHILPOT, J. W., see WALKER, E. ..... July, 247–252
PICARD, R. R., see BERK, K. N. ..... April, 79–89
33. PIEPEL, G. F., *Screening Designs for Constrained Mixture Experiments Derived from Classical Screening Designs—An Addendum* ..... April, 96–101
PIGNATIELLO, J. J., JR., see RUNGER, G. C. ..... April, 135–155
34. QUESENBERRY, C. P., *SPC Q Charts for a Binomial Parameter p: Short or Long Runs* ..... July, 239–246
35. QUESENBERRY, C. P., *SPC Q Charts for a Poisson Parameter λ: Short or Long Runs* ..... October, 296–303
36. QUESENBERRY, C. P., *SPC Q Charts for Start-Up Process and Short or Long Runs* ..... July, 213–224
37. RUNGER, G. C. AND PIGNATIELLO, J. J., JR., *Adaptive Sampling for Process Control* ..... April, 135–155
38. RYAN, T. P., *Discussion* ..... July, 200–202
SAMARANAYAKE, V. A., see PATEL, J. K. ..... October, 270–286
39. SANIGA, E. M., *Joint Statistical Design of $\bar{X}$ and R Control Charts* ..... April, 156–162
40. SCHMIDT, R. L. AND PFEIFER, P. E., *Economic Selection of the Mean and Upper Limit for a Canning Problem* ..... October, 312–317
41. SPIRING, F. A., *Assessing Process Capability in the Presence of Systematic Assignable Cause* ..... April, 125–134
42. STEPHENSON, W. R., *A Computer Program for Quick and Easy Analysis of Unreplicated Factorials* January, 63–67
43. TSENG S.-T. AND WU, T.-Y., *Selecting the Best Manufacturing Process* ..... January, 53–62
44. VAUGHAN, T. S. AND PETERS, M. H., *Economic Design of Fraction Nonconforming Control Charts with Multiple State Changes* ..... January, 32–43
45. WALKER, E.; PHILPOT, J. W.; AND CLEMENT, J., *False Signal Rates for the Skewhart Control Chart with Supplementary Runs Rules* ..... July, 247–252
WOODALL, W. H., see FALTIN, F. W. ..... July, 194–197
WU, T.-Y., see TSENG, S.-T. ..... January, 53–62
ZHUANG, Z., see JARAIEDI, M. ..... July, 253–258

DEPARTMENTS

Computer Programs

9. CROSIER, R. B., *FORTRAN Programming Techniques* ..... October, 348–354
15. GAN., F. F., *Computing the Percentage Points of the Run Length Distribution of an Exponentially Weighted Moving Average Control Chart* ..... October, 359–366

18. JARAIEDI, M. AND ZHUANG ZIQUING, *Determination of Optimal Design Parameters of $\bar{X}$ Charts When there is a Multiplicity of Assignable Causes* ..... July, 253–258
19. JIN, C. AND DAVIS, R. B., *Calculation of Average Run Lengths for Zone Control Charts with Specified Zone Scores* ..... October, 355–358
38. SANIGA, E. M., *Joint Statistical Design of $\bar{X}$ and R Control Charts* ..... April, 156–162
41. STEPHENSON, W. R., *A Computer Program for Quick and Easy Analysis of Unreplicated Factorials* January, 63–67

Technical Aids

27. NELSON, L. S., *Additional Critical Values for Multiple Comparisons by Cluster Analysis* ..... October, 366–368
28. NELSON, L. S., *Polynomial Interpolation* ..... July, 259–262
29. NELSON, L. S., *Power in Comparing Poisson Means: I. One-Sample Test* ..... January, 68–70
30. NELSON, L. S., *Power in Comparing Poisson Means: II. Two-Sample Test* ..... April, 163–166

Book Reviews

BARKER, T. B., *Engineering Quality by Design: Interpreting the Taguchi Approach* .. Kailash Kapur October, 371
BESTERFIELD, D. H., *Quality Control, 3rd ed.* ..... B. L. Foote April, 171–172
BREBBIA, C. A. AND ORSZAG, S. A., *Reliability and Optimization of Structural Systems '88* ..... Michael Pecht January, 74
BURR, J. T., *SPC Tools for Operators* ..... Lonnie C. Vance April, 177–178
CALVIN, T. W., *How and When to Perform Bayesian Acceptance Sampling* ... Thomas A. Mazzuchi October, 371–373
CHATFIELD, C., *The Analysis of Time Series, 4th ed.* ..... Richard W. Kulp April, 170–171
CORNELL, J. A., *Experiments With Mixtures: Designs, Models and the Analysis of Mixture Data, 2nd ed.* ..... Lynne B. Hare April, 168–169
CORNELL, J. A., *How to Apply Response Surface Methodology* ..... Don Edwards October, 370–371
DALEY, D. J. AND VERE-JONES, D., *An Introduction to the Theory of Point Processes* ..... Maurizio Guida April, 173–174
DEHNAD, K., *Quality Control, Robust Design, and the Taguchi Method* ..... Kailash C. Kapur April, 173
DOBBINS, J. H., *Software Quality Assurance and Evaluation* ..... William E. Thompson July, 264
DUMMER, G. W. A. AND WINTON, R. C., *An Elementary Guide to Reliability, 4th ed.* ..... Lawrence Leemis July, 267–268
GHOSH, S., *Statistical Design and Analysis of Industrial Experiments* ..... G. Geoffrey Vining October, 373
GRANT, E. L. AND LEAVENWORTH, R. S., *Statistical Quality Control, 6th ed.* ..... Lloyd S. Nelson July, 266–267
HEIBERGER, R. M., *Computation for the Analysis of Designed Experiments* ..... Paul Velleman July, 264–265
HUNGER, A., *Testability Analysis: A Survey on Methods and Applications* ..... Michael Pecht January, 74–75
JONES, J. V., *Engineering Design* ..... Heather B. Dussault October, 373
KANE, V. E., *Defect Prevention: Use of Simple Statistical Tools* ..... Edward P. Coleman January, 76
KRISMANN, C., *Quality Control: An Annotated Bibliography through 1988* ..... Peter R. Nelson January, 77
LAWRENCE, K. D. AND ARTHUR, J. L., *Robust Regression; Analysis and Applications* ..... G. Geoffrey Vining April, 175–176
MARRIOTT, F. H. C., *A Dictionary of Statistical Terms, 5th ed.* ..... Lloyd S. Nelson April, 167–168
MCCULLAGH, P. AND NELDER J. A., *Generalized Linear Models, 2nd ed.* ..... Paulette Johnson July, 263–264
MCWILLIAMS, T. P., *How to Use Sequential Statistical Methods* ..... Moshe Pollak October, 374–375
MICHAELS, J. V. AND WOOD, W. P., *Design to Cost* ..... Hefin Rowlands January, 73–74
MILLER, A. J., *Subset Selection in Regression* ..... M. Knott July, 267
MONTGOMERY, D. C., *Design and Analysis of Experiments, 3rd ed.* ..... Peter R. Nelson October, 375
MONTGOMERY, D. C., *Introduction to Statistical Quality Control, 2nd ed.* ..... Hiroshi Ohta October, 369–370
MORRISON, D. F., *Multivariate Statistical Methods, 3rd. ed.* ..... Laurence L. George January, 75
NETER, J.; WASSERMAN, W.; AND KUTNER, M., *Applied Linear Regression Models, 2nd ed.,* ..... Lawrence Leemis January, 76–77
OTT, E. R. AND SCHILLING, E. G., *Process Quality Control, 2nd ed.* ..... Peter R. Nelson January, 71–73
OWEN, M., *SPC and Continuous Improvement* ..... Douglas J. DePriest April, 175

RAHEJA, D. G., *Assurance Technologies: Principles and Practices* ..... Irwin A. Feigenbaum July, 265–266
RATKOWSKY, D. A., *Handbook of Nonlinear Regression Models* ..... Victor W. Lowe, Jr. April, 172–173
RELYEA, D. B., *Practical Applications of SPC in the Wire & Cable Industry* ..... August B. Mundel April, 169–170
ROSS, S. M., *A Course in Simulation* ..... James J. Swain April, 176–177
STIGLER, S., *The History of Statistics: The Measurement of Uncertainty Before 1900* ..... Samuel S. Shapiro April, 168
VAUGHAN, R. C., *Quality Assurance* ..... Douglas C. Brauer October, 370
WADSWORTH, H. M., JR., *Handbook of Statistical Methods for Engineers and Scientists* ..... D. B. Owen January, 71

Book Reviewers

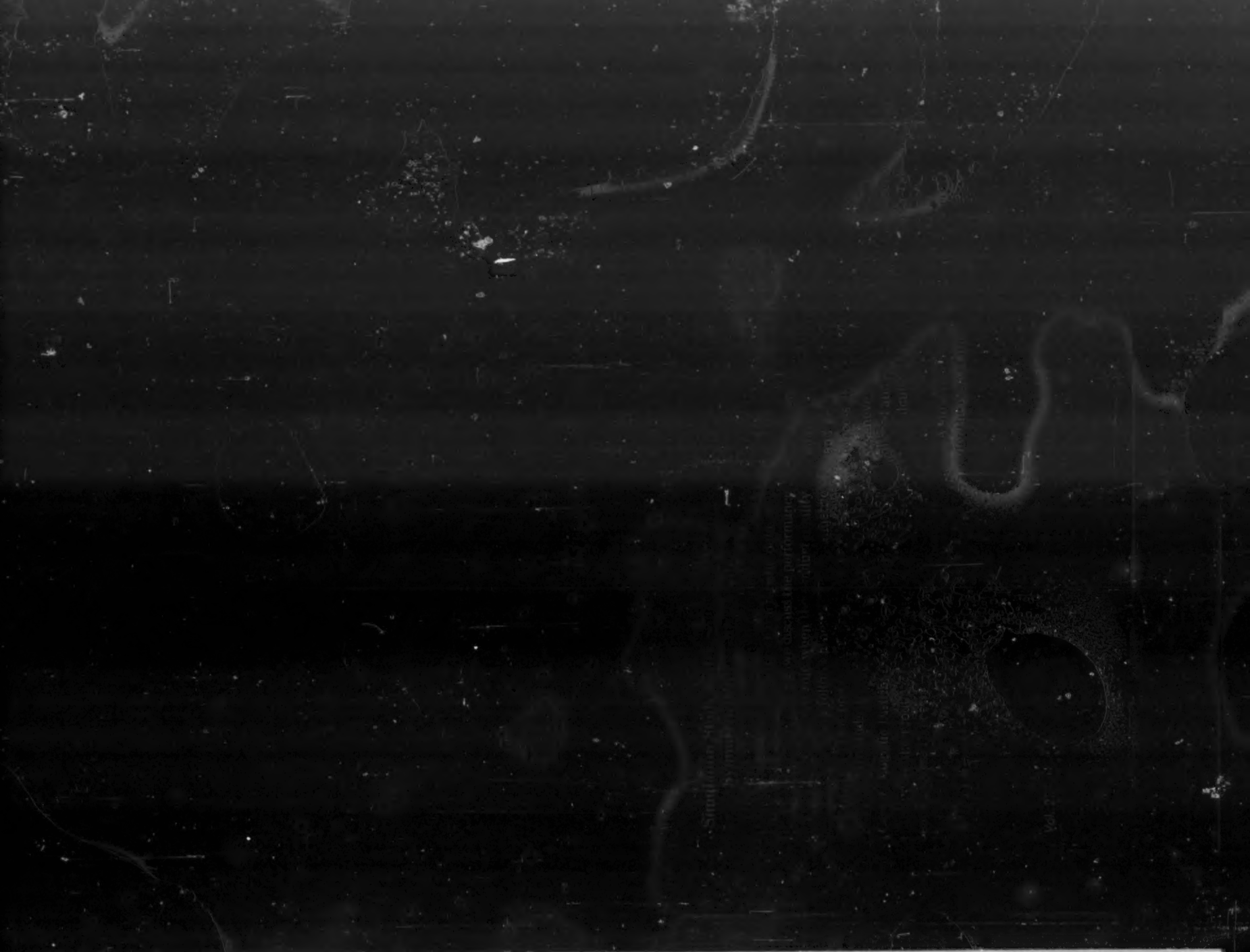
Brauer, D. C. ..... October, 370
Coleman, E. P. ..... January, 76
DePriest, D. J. ..... April, 175
Dussault, H. B. ..... October, 373
Edwards, D. ..... October, 370–371
Feigenbaum, I. A. ..... July, 265–266
Foote, B. L. ..... April, 171–172
George, L. L. ..... January, 75
Guida, M. ..... April, 173–174
Mazzuchi, T. A. ..... October, 371–373
Mundel, A. B. ..... April, 169–170
Nelson, L. S. ..... April, 167–168
Nelson, L. S. ..... July, 266–267
Nelson, P. R. ..... January, 71–73
Nelson, P. R. ..... January, 77
Nelson, P. R. ..... October, 375
Ohta, H. ..... October, 369–370
Owen, D. B. ..... January, 71
Pecht, M. ..... January, 74–75
Hare, L. B. ..... April, 168–169
Johnson, P. ..... July, 263–264
Kapur, K. ..... October, 371
Kapur, K. C. ..... April, 173
Knott, M. ..... July, 267
Kulp, R. W. ..... April, 170–171
Leemis, L. ..... January, 76–77
Leemis, L. ..... July, 267–268
Lowe, V. W., Jr. ..... April, 172–173
Pollak, M. ..... October, 374–375
Rowlands, H. ..... January, 73–74
Shapiro, S. S. ..... April, 168
Swain, J. J. ..... April, 176–177
Thompson, W. E. ..... July, 264
Vance, L. C. ..... April, 177–178
Velleman, P. ..... July, 264–265
Vining, G. G. ..... April, 175–176
Vining, G. G. ..... October, 373–374

MISCELLANEOUS

Corrigenda ..... October, 382
Editorial ..... October, 269
Editorial Collaborators ..... October, 381

KEY WORDS

The numbers used with the key words are the numbers assigned to the articles listed on the previous pages. They are not page numbers.

Analysis of Means, 42
Accuracy, 5
Attributes Data, 31
Autocorrelation, 27
Average Run Length, 15, 20, 37
Best Manufacturing Process, 43
β-Content Tolerance Interval, 14
Binomial Distribution, 31, 34
Bivariate Normal Distribution, 5
c Charts, 35
Canning Problem, 40
Clustering, 28
Computer Program, 39
Computer Program Optimization, 10
Confidence Limits, 2
Consumer Risk, 11
Control Charts, 27, 34, 36, 37, 39
Control Scheme, 37
Cost Modeling, 11
Critical Values, 28
CUSUM Chart, 7
Data Analysis, 4
Design of Experiments, 21
Economic Design, 19, 44
Economic Selection, 40
Exponential Distribution, 3
Exponentially Weighted Moving Average, 18, 27
Finite Population, 14
Factorial Experiments, 42

Fractional Factorials, 4
Fractional Factorial Design, 33
Fractional Factorial Plans, 21
Gaussian Elimination, 20
Grubbs Estimators, 5
Grubbs-Type Model, 11
Half-Normal Plots, 4
Head Starts, 15
Hodges-Lehmann Estimator, 1
Hypothesis Testing, 30, 31
Integral Equation, 15
Interlaboratory Testing, 11
Job Shops, 35, 36
Lagrangian Interpolation, 29
Lambda Plot, 17
Loss Function, 8
Low-Volume Manufacturing, 23
Many-One Statistics, 9
Markov Chain, 20
Measurement Error, 12
Median, 9
Modified Likelihood Ratio Principle, 43
Modified Likelihood Ratio Selection Rule, 43
Multiple Assignable Causes, 19
Multiple Comparisons, 9, 28
Multiresponse Experiment, 17
Nonconformities, 35
Nonparametric Control Chart, 1
Nonparametric Methods, 9
Nonparametric Procedure, 18
Normal Approximation, 30, 31
Normal Distribution, 16
np Control Charts, 44
Numerical Integration, 16
One-Sample Tests, 30, 31
One-Sided Alternatives, 9
One-Way Layout, 9
Optimal Experimental Design, 33
Optimum Set Point, 6
Optimum Target Value, 25
Orthogonal Arrays, 21
p Chart, 7
Pareto Chart, 22
Plackett-Burman Design, 33
Poisson Distribution, 30, 31
Polynomial Interpolation, 29
Pooling, 4
Power of Test, 30, 31
Precision, 5
Prediction Intervals, 3
Probability Function, 16
Process Capability, 8, 41
Process Capability Index, 41
Process Capability Ratio Index, 43
Process Centering, 8
Process Control, 37
Process Control Economics, 6, 25
Process Control Optimization, 44
Process Distribution, 43
Process Optimization, 6, 25
Process Potential, 8
Quality, 40
Quality Management, 22
Ranks, 18
Reliability, 2
Repeatability, 11
Reproducibility, 11
Robustness, 18
Run Length, 18
Runs Tests, 45
Sample Size, 2, 30, 31
Scaled Chi-Square Approximation, 8
Screening Experiment, 17
Selection Rule, 43
Sensitivity Analysis, 15
Shewhart Control Chart, 18, 37, 45
Short Runs, 34, 35, 36
Simultaneous Test, 5
Start-Up Processes, 35, 36
Statistical Design, 39
Statistical Process Control, 7, 16, 22, 45
Statistical Quality Control, 22
Structured Programming, 10
Systematic Assignable Cause, 41
Taguchi, 4
Taguchi Methods, 21
Target Value, 8
Test of Two Poisson Means, 31
Test Plans, 2
Time Series Models, 27
Tolerances, 12
Tool Wear, 41
Transformation, 17, 29
Treatments versus Standard, 9
Two-Sample Tests, 31
Type I Error, 45
u Charts, 35
Unknown Parameters, 36
Unreplicated Fractional Experiment, 17
Variable Sampling Frequency, 37
Variation from Target, 8
Walsh Averages, 1
Weibull Degradation Model, 2
Wilcoxon Signed Rank Statistic, 1
$\bar{X}$ Charts, 19
XVERT Algorithm, 33
Zone Control Chart, 20